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Time-Resolved Studies of Single-Event-Upset effects in Optical Data Receiver for the First LHC Upgrade Phase of the ATLAS Pixel Detector.

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A multi-channel optical receiver board housing a PiN array coupled to an amplifier-and-decoding ASIC designed in 130 nm CMOS process for bi-phase-mark encoded input signals, was exposed to a proton beam of 24 GeV/c momentum together with a reference receiver board containing the same ASIC coupled to an electrical input-signal-source instead. The 40 MHz clock and 40 Mbit/s data signals supplied to the devices under test, were restored directly on both boards and then transmitted back to the counting room for on-line checking of consistency. In the case of a data bit error or a missing clock transition, indicating an occurrence of a SEU, a sequence of time aligned data bits and corresponding clock states were recorded binary and in part as oscilloscope-waveforms for off-line analyses. Measurements were performed using a custom-developed, FPGA-based, DAQ system for input signals covering a certain range of optical and electrical amplitudes. We present results obtained from the latest 2010 run at the CERN irradiation facility, including the SEU crosssection dependence on input signal amplitude, for various types of effects on clock and data consistency, along with the time-resolved structure of the SEU incidents.

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